

ABSTRACT OF THE DISCLOSURE

Method for determining a repair solution for a memory module in a test system, memory areas of the memory module being successively tested in order to obtain, for each memory area, a defect datum which specifies whether the respective memory area is defective, wherein defect addresses, the address values of which specify the defective memory areas of the memory module, are generated from addresses of the memory areas and the associated defect data, the defect addresses being stored in the test system, the repair solution being determined from the stored defect addresses.